

Search Notes

Application/Control No.

10/506,568

Examiner

KEVIN L. LEE

Applicant(s)/Patent under
Reexamination

WEH ET AL.

Art Unit

3753

SEARCHED

Class	Subclass	Date	Examiner
137	614.03 614.04 614.05 614.06	12/5/2006	KL
251	149.9 149.6		
285	314-317		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search	12/5/2006	KL